

## Improved Poisson-disk Sampling for Meshing applications

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Poisson-disk sampling is similar to sphere packings: points have a minimum separation distance and the disks cover the domain. Disk centers are randomly placed. The method is popular in computer graphics because the random distribution avoids visual artifacts. This randomness can also be useful to avoid mesh-induced non-physical phenomena in simulations. We describe several new approaches to Poisson-disk sampling and resampling to generate and improve simplicial meshes in d-dimensional spaces. We produce provably-good tessellations, with quality bounds similar to (or better) than deterministic Delaunay refinement methods. It is inherently easier for our methods to follow a sizing function because of the close connection between Poisson-disks and the local mesh size. We show results for the uniform and the non-uniform case. We show several applications to examples to demonstrate the efficiency of our methods.

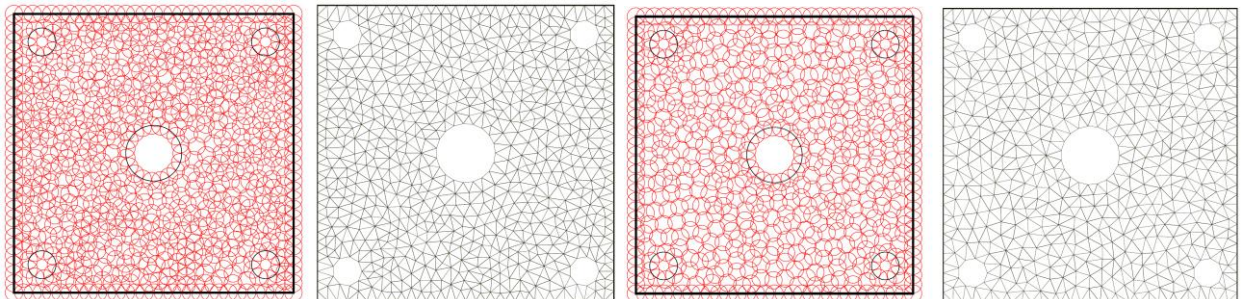


Figure 1: A disk-packing generated using a Delaunay Refinement method satisfies the packing conditions of MPS and hence the associated Delaunay mesh is associated with guaranteed quality (left). Understanding the relation between the packing condition and the desired quality allows significant reduction of the Steiner points count while preserving the quality bounds and the sizing function (right).

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